

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 212812US2		SERIAL NO. 09/930,202	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takashi IPPOSHI, et al.			
				FILING DATE RCE Filed Herewith		GROUP 2815	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
	AB						
	AC						
	AD						
	AE						
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	AH						
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	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
JN	AO	JP05090117	04/09/93	JAPAN W/ENGLISH ABSTRACT			X
	AP	JP01241854	09/26/89	JAPAN W/ENGLISH ABSTRACT			X
	AQ	JP56060061	05/23/81	JAPAN W/ENGLISH ABSTRACT			X
	AR	JP06005569	01/14/94	JAPAN W/ENGLISH ABSTRACT			X
	AS						
	AT						
	AU						
	AV						
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
JN	AW	Effect of <100> Channel Direction for High Performance SCE Immune pMOSFET with Less Than 0.15µm Gate Length, H. Sayama, et al.; International Electron Devices Meeting 1999; IEDM. Technical Digest, Washington, DC; Dec. 5-8, 1999; New York, NY; IEEE US; pp. 657-660.					
	AX	Smart Cut: A Promising New SOI Material Technology; Bruel, M. et al.; 1995 IEEE International SOI Conference Proceedings; Tuscon, Oct. 3-5, 1995; Proceedings of the Annual SOS/SOI Technology Conference. (From 1991 Proceedings of the International SOI Conference.) Silicon-on-Insulator Technology and Devices, New York, Oct. 3, 1995; pp. 178-179.					
	AY	High-Quality Epitaxial Layer Transfer (Eltran) by Bond and Etch-Back of Porous Si; Sato, et al.; 1995 IEEE International SOI Conference Proceedings. Tuscon, Oct. 3-5, 1995, Proceedings of the Annual SOS/SOI Technology Conference. (From 1991 Proceedings of the International SOI Conference.) Silicon-On-Insulator Technology and Devices, New York, Oct. 3, 1995, pp. 176-177.					
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner JOSEPH NAVYEN					Date Considered 6/29/04		
*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.							